

Chirag Gupta

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9165384/publications.pdf>

Version: 2024-02-01

33
papers

913
citations

516215

16
h-index

476904

29
g-index

33
all docs

33
docs citations

33
times ranked

679
citing authors

#	ARTICLE	IF	CITATIONS
1	In Situ O_2 and Ga Interlayer-Based Vertical Trench MOSFETs (OG-FET) on Bulk GaN substrates. IEEE Electron Device Letters, 2017, 38, 353-355.	2.2	130
2	Demonstration of ultra-small ($\sim 1/4\mu\text{m}$) 632 nm red InGaN micro-LEDs with useful on-wafer external quantum efficiency ($>0.2\%$) for mini-displays. Applied Physics Express, 2021, 14, 011004.	1.1	96
3	OG-FET : An In-Situ O_2 and Ga Interlayer-Based Vertical Trench MOSFET. IEEE Electron Device Letters, 2016, 37, 1601-1604.	2.2	63
4	Demonstrating >1.4 kV OG-FET performance with a novel double field-plated geometry and the successful scaling of large-area devices. , 2017, , .		53
5	Large-Area In-Situ O_2 and Ga Interlayer-Based Vertical Trench MOSFET (OG-FET). IEEE Electron Device Letters, 2018, 39, 711-714.	2.2	52
6	High breakdown voltage p-n diodes on GaN on sapphire by MOCVD. Physica Status Solidi (A) Applications and Materials Science, 2016, 213, 878-882.	0.8	51
7	Comparing electrical performance of GaN trench-gate MOSFETs with a-plane and m-plane sidewall channels. Applied Physics Express, 2016, 9, 121001.	1.1	49
8	Color-tunable $\sim 10\mu\text{m}^2$ InGaN micro-LEDs on compliant GaN-on-porous-GaN pseudo-substrates. Applied Physics Letters, 2020, 117, .	1.5	44
9	Growth of strain-relaxed InGaN on micrometer-sized patterned compliant GaN pseudo-substrates. Applied Physics Letters, 2020, 116, .	1.5	38
10	First Demonstration of AlSiO as Gate Dielectric in GaN FETs; Applied to a High Performance OG-FET . IEEE Electron Device Letters, 2017, 38, 1575-1578.	2.2	37
11	Demonstration of a GaN/AlGaIn Superlattice-Based p-Channel FinFET With High ON-Current. IEEE Electron Device Letters, 2020, 41, 220-223.	2.2	36
12	Fabrication of relaxed InGaN pseudo-substrates composed of micron-sized pattern arrays with high fill factors using porous GaN. Semiconductor Science and Technology, 2019, 34, 115020.	1.0	30
13	Improved Dynamic R_{ON} of GaN Vertical Trench MOSFETs (OG-FETs) Using TMAH Wet Etch. IEEE Electron Device Letters, 2018, 39, 1030-1033.	2.2	25
14	An improved methodology for extracting interface state density at $\text{Si}_3\text{N}_4/\text{GaN}$. Applied Physics Letters, 2020, 116, .	1.5	23
15	Compliant Micron-Sized Patterned InGaN Pseudo-Substrates Utilizing Porous GaN. Materials, 2020, 13, 213.	1.3	22
16	Metalorganic chemical vapor deposition and characterization of (Al,Si)O dielectrics for GaN-based devices. Japanese Journal of Applied Physics, 2016, 55, 021501.	0.8	20
17	First demonstration of improvement in hole conductivity in <i>c</i> -plane III-Nitrides through application of uniaxial strain. Japanese Journal of Applied Physics, 2019, 58, 030908.	0.8	16
18	Net negative fixed interface charge for Si_3N_4 and SiO_2 grown in situ on 000-1 N-polar GaN. Applied Physics Letters, 2019, 115, 032103.	1.5	15

#	ARTICLE	IF	CITATIONS
19	Method of growing elastically relaxed crack-free AlGa _x N on GaN as substrates for ultra-wide bandgap devices using porous GaN. Applied Physics Letters, 2020, 117, .	1.5	15
20	Ultra-high silicon doped N-polar GaN contact layers grown by metal-organic chemical vapor deposition. Semiconductor Science and Technology, 2020, 35, 095002.	1.0	12
21	Impact of Trench Dimensions on the Device Performance of GaN Vertical Trench MOSFETs. IEEE Electron Device Letters, 2017, 38, 1559-1562.	2.2	10
22	First report of scaling a normally-off in-situ oxide, GaN interlayer based vertical trench MOSFET (OG-FET)., 2017, , .		9
23	First experimental demonstration and analysis of electrical transport characteristics of a GaN-based HEMT with a relaxed InGa _x N channel. Semiconductor Science and Technology, 2020, 35, 075007.	1.0	9
24	Patterned IIIâ€Nitrides on Porous GaN: Extending Elastic Relaxation from the Nanoâ€to the Micrometer Scale. Physica Status Solidi - Rapid Research Letters, 2021, 15, 2100234.	1.2	9
25	Pâ€n junction diodes with polarization induced p-type graded In_x/i>Ga_{1â€}N layer. Semiconductor Science and Technology, 2017, 32, 105013.	1.0	8
26	Vertical GaN and Vertical Ga₂O₃ Power Transistors: Status and Challenges. Physica Status Solidi (A) Applications and Materials Science, 2022, 219, .	0.8	7
27	Exploring metalorganic chemical vapor deposition of Si-alloyed Al ₂ O ₃ dielectrics using disilane. Journal of Crystal Growth, 2017, 464, 54-58.	0.7	6
28	Maskless regrowth of GaN for trenched devices by MOCVD. Applied Physics Letters, 2017, 111, .	1.5	6
29	Abrupt GaN/p-GaN:Mg junctions grown via metalorganic chemical vapor deposition. Applied Physics Express, 2017, 10, 111002.	1.1	5
30	Flatband voltage stability and time to failure of MOCVD-grown SiO₂ and Si₃N₄ dielectrics on N-polar GaN. Applied Physics Express, 2019, 12, 121001.	1.1	5
31	Corrections to â€In Situ</i> Oxide, GaN Interlayer-Based Vertical Trench MOSFET (OG-FET) on Bulk GaN Substratesâ€™ [Mar 17 353-355]. IEEE Electron Device Letters, 2018, 39, 316-316.	2.2	4
32	Comparing electrical characteristics of in situ and ex situ Al₂O₃/GaN interfaces formed by metalorganic chemical vapor deposition. Applied Physics Express, 2018, 11, 041002.	1.1	4
33	Reverse breakdown studies of GaN MOSCAPs and their implications in vertical GaN power devices. Journal of Applied Physics, 2019, 125, 124101.	1.1	4